

Arria 10 DDR4 IP Parameterization

Selecting the DDR4 IP timing parameters from a Micron DDR4 device data sheet :

Memory Topology and Memory Timing tabs



Presets

- ◀ Based on JEDEC specifications
- ◀ Use as a starting point
 - Select a preset close to the requirement
 - ◀ Memory Format
 - Discrete Device
 - DIMM (UDIMM, RDIMM, LRDIMM)
 - ◀ Configuration
 - Maximum Throughput (DDR4-xxxx)
 - CAS latency
 - Rank/chip select
 - Capacity
 - Device Width
- ◀ Then modify as required
 - Some memory timing parameters may need to be changed
- ◀ DDR4 DIMMS
 - To find the actual memory device used on the DIMM
 - ◀ Get the Base device part number from the DIMM datasheet

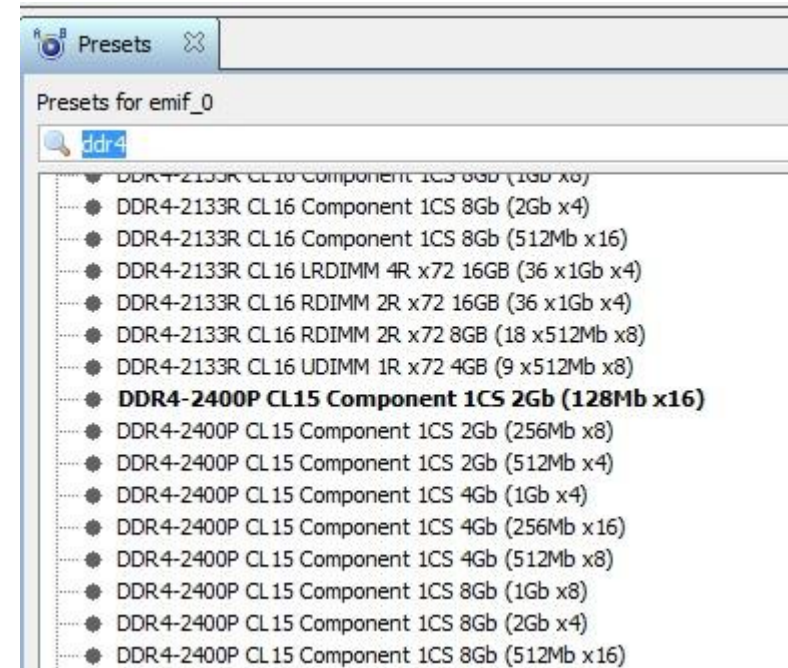


Table 3: Part Numbers and Timing Parameters – 4GB Modules

Base device: MT40A512M8,¹ 4Gb DDR4 SDRAM

Part Number ²	Module Density	Configuration	Mod Bandw
MTA8ATF51264AZ-2G3__	4GB	512 Meg x 64	19.2 G

Memory Timing 1

- Memory device **Speed bin** defines the maximum data rate that the memory device can support
 - Get from the DDR4 memory device part number **speed grade**

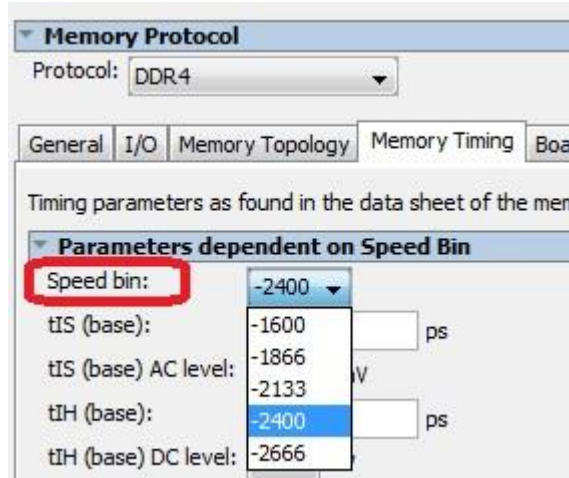


Table 1: Key Timing Parameters

Speed Grade	Data Rate (MT/s)
-083E ^{1, 2, 3, 4}	2400
-093F ^{1, 2, 3}	2133
-093E ^{1, 2}	2133
-107E ¹	1866

- Speed grade may have a letter suffix
 - Indicates CAS latency, tRCD, tRP

Memory Topology 1

Memory Topology -> Mode Register Settings : Latencies

-> Use Memory Device data sheet **Speed bin table**

– Take into account

Memory speed grade

DDR4 clock period tCK

DBI

☒ Data mask
☐ Write DBI
☐ Read DBI
☒ Enable ALERT#/PAR pins
 ALERT# pin placement: Automatically select a location

Mode Register Settings

Mode Register 0
 Burst Length: Fixed BL8
 Read Burst Type: Sequential
 Memory CAS latency setting: 15

Mode Register 1
 Output drive strength setting: 00 - RZQ/7
 Memory additive CAS latency setting: Disabled
 ODT Rtt nominal value: ODT Disabled

Mode Register 2
 Auto self-refresh method: Manual - Normal Temp. Range
 Memory write CAS latency setting: 12
 Dynamic ODT (Rtt_WR) value: RZQ/1

Table 139: DDR4-2400 Speed Bins and Operating Conditions

DDR4-2400 Speed Bin		-083F		-083E		-083		Unit
CL-nRCD-nRP		15-15-15		16-16-16		17-17-17		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	
Internal READ command to first data	t _{AA}	12.5	18.00	13.32	18.00	14.16	18.00	ns

READ: nonDBI	READ: DBI	WRITE	Symbol	Min	Max	Min	Max	Min	Max	Unit
CL = 9	CL = 11	CWL = 9	tCK	1.5	1.6	1.5	1.6	Reserved		ns
CL = 10	CL = 12	CWL = 9	tCK	1.5	1.6	Reserved		1.5	1.6	ns
CL = 10	CL = 12	CWL = 9, 11	tCK	Reserved		Reserved		Reserved		ns
CL = 11	CL = 13	CWL = 9, 11	tCK	Reserved		1.25	<1.5	1.25	<1.5	ns
CL = 12	CL = 14	CWL = 9, 11	tCK	1.25	<1.5	1.25	<1.5	1.25	<1.5	ns
CL = 12	CL = 14	CWL = 10, 12	tCK	Reserved		Reserved		Reserved		ns
CL = 13	CL = 15	CWL = 10, 12	tCK	Reserved		1.071	<1.25	1.071	<1.25	ns
CL = 14	CL = 16	CWL = 10, 12	tCK	1.071	<1.25	1.071	<1.25	1.071	<1.25	ns
CL = 14	CL = 17	CWL = 11, 14	tCK	Reserved		Reserved		Reserved		ns
CL = 15	CL = 18	CWL = 11, 14	tCK	Reserved		0.937 ⁶	<1.071	0.937	<1.071	ns
CL = 16	CL = 19	CWL = 11, 14	tCK	0.937	<1.071	0.937	<1.071	0.937	<1.071	ns
CL = 15	CL = 18	CWL = 12, 16	tCK	0.833	<0.937	Reserved		Reserved		ns
CL = 16	CL = 19	CWL = 12, 16	tCK	0.833	<0.937	0.833	<0.937	Reserved		ns
CL = 17	CL = 20	CWL = 12, 16	tCK	0.833	<0.937	0.833	<0.937	0.833	<0.937	ns
CL = 18	CL = 21	CWL = 12, 16	tCK	0.833	<0.937	0.833	<0.937	0.833	<0.937	ns
Supported CL settings				9, 10, 12, 14-18		9, 11-18		10-18		nCK
Supported CL settings with read DBI				11, 12, 14, 16-21		13-16, 18-21		12-16, 18-21		nCK
Supported CWL settings				9, 10, 11, 12, 14, 16		9, 10, 11, 12, 14, 16		9, 10, 11, 12, 14, 16		nCK

Memory Timing 2

Presets are typically for the DDR4 device speed grade **clocked at its highest frequency**

Some parameters may need to be modified :

- Clocking at lower frequency
- Using an industrial temperature DDR4 device
 - ◀ Refresh rate t_{REFI} -> 3.9us

General	I/O	Memory Topology	Memory Timing	Board Timing	Controller	Diagnostics
Timing parameters as found in the data sheet of the memory device.						
Parameters dependent on Speed Bin						
Speed bin:	-2400					
tIS (base):	60	ps				
tIS (base) AC level:	100	mV				
tIH (base):	95	ps				
tIH (base) DC level:	75	mV				
tdIVW_dj:	0.1	cycles				
VdIVW_total:	136	mV				
tDQSQ:	66	ps				
tQH:	0.38	cycles				
tDQSQ:	165	ps				
tQSS:	0.27	cycles				
tQSH:	0.38	cycles				
tDSH:	0.18	cycles				
tDSS:	0.18	cycles				
tWLS:	108.0	ps				
tWLH:	108.0	ps				
tINIT:	500	us				
tMRD:	8	cycles				
tRAS:	32.0	ns				
tRCD:	12.5	ns				
tRP:	12.5	ns				
tWR:	15.0	ns				
Parameters dependent on Speed Bin, Operating Frequency, and Page Size						
Update the following as you change the operating frequency, even if the device speed bin has not changed.						
tRRD_S:	7	cycles				
tRRD_L:	8	cycles				
tFAW:	30.0	ns				
tCCD_S:	4	cycles				
tCCD_L:	6	cycles				
tWTR_S:	3	cycles				
tWTR_L:	9	cycles				
Parameters dependent on Density and Temperature						
Update the following as you change the physical memory device density. Incorrect values can cause data corruption.						
tRFC:	160.0	ns				
tREFI:	7.8	us				

Memory Timing 3

- From the Electrical Characteristics and AC Timing Parameters table
 - Use the DDR4-xxxx column that the device is rated for
 - eg 1200MHz device -> use DDR4-2400
- From the Electrical Characteristics and AC Timing Parameters table
 - Use the DDR4-xxxx column that the device is rated for
 - Calculate values as required using :
 - Page size (0.5K, 1K or 2K)
 - Memory Clock Frequency (tCK)
- See next slide for data sheet extracts

General | I/O | Memory Topology | **Memory Timing** | Board Timing | Controller | Diagnostics

Timing parameters as found in the data sheet of the memory device.

Parameters dependent on Speed Bin

Speed bin: -2400

tIS (base):	60	ps
tIS (base) AC level:	100	mV
tIH (base):	95	ps
tIH (base) DC level:	75	mV
tdIVW_dj:	0.1	cycles
VdIVW_total:	136	mV
tDQSQ:	66	ps
tQH:	0.38	cycles
tDQSC:	165	ps
tDQSS:	0.27	cycles
tQSH:	0.38	cycles
tDSH:	0.18	cycles
tDSS:	0.18	cycles
tWLS:	108.0	ps
tWLH:	108.0	ps
tINIT:	500	us
tMRD:	8	cycles
tRAS:	32.0	ns
tRCD:	12.5	ns
tRP:	12.5	ns
tWR:	15.0	ns

Parameters dependent on Speed Bin, Operating Frequency, and Page Size

Update the following as you change the operating frequency, even if the device speed bin has not changed.

tRRD_S:	7	cycles
tRRD_L:	8	cycles
tFAW:	30.0	ns
tCCD_S:	4	cycles
tCCD_L:	6	cycles
tWTR_S:	3	cycles
tWTR_L:	9	cycles

Parameters dependent on Density and Temperature

Update the following as you change the physical memory device density. Incorrect values can cause data corruption.

tRFC:	160.0	ns
tREFI:	7.8	us

Memory Timing 4

Extracts from a Micron Memory DDR4 Datasheet

Table 2: Addressing

Parameter	1024 Meg x 4	512 Meg x 8	256 Meg x 16
Number of bank groups	4	4	2
Bank group address	BG[1:0]	BG[1:0]	BG0
Bank count per group	4	4	4
Bank address in bank group	BA[1:0]	BA[1:0]	BA[1:0]
Row addressing	64K (A[15:0])	32K (A[14:0])	32K (A[14:0])
Column addressing	1K (A[9:0])	1K (A[9:0])	1K (A[9:0])
Page size ¹	512B / 1KB ²	1KB	2KB

Notes: 1. Page size is per bank, calculated as follows:
Page size = $2^{\text{COLBITS}} \times \text{ORG}/8$, where COLBITS = the number of column address bits and ORG = the number of DQ bits.

Table 143: Electrical Characteristics and AC Timing Parameters (Continued)

Parameter	Symbol	DDR4-1600		DDR4-1866		DDR4-2133		DDR4-2400		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
DLL locking time	^t DLLK	597	–	597	–	768	–	768	–	CK
CMD, ADDR setup time to CK _t , CK _c referenced to V _{IH(AQ)} and V _{IL(AQ)} levels	Base	^t IS	115	–	100	–	80	–	62	ps
	V _{REFCA}	^t IS _{VREF}	215	–	200	–	180	–	162	ps
CMD, ADDR hold time to CK _t , CK _c referenced to V _{IH(DQ)} and V _{IL(DQ)} levels	Base	^t IH	140	–	125	–	105	–	87	ps
	V _{REFCA}	^t IH _{VREF}	215	–	200	–	180	–	162	ps
CTRL, ADDR pulse width for each input	^t IPW	600	–	525	–	460	–	410	–	ps
ACTIVATE to internal READ or WRITE delay	^t RCD	See Speed Bin Tables for ^t RCD								ns
PRECHARGE command period	^t RP	See Speed Bin Tables for ^t RP								ns
ACTIVATE-to-PRECHARGE command period	^t RAS	See Speed Bin Tables for ^t RAS								ns
ACTIVATE-to-ACTIVATE or REF command period	^t RC	See Speed Bin Tables for ^t RC								ns
ACTIVATE-to-ACTIVATE command period to different bank groups for 1/2KB page size	^t RRD_S (1/2KB)	MIN = greater of 4CK or 5ns	MIN = greater of 4CK or 4.2ns	MIN = greater of 4CK or 3.7ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	CK
ACTIVATE-to-ACTIVATE command period to different bank groups for 1KB page size	^t RRD_S (1KB)	MIN = greater of 4CK or 5ns	MIN = greater of 4CK or 4.2ns	MIN = greater of 4CK or 3.7ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	MIN = greater of 4CK or 3.3ns	CK
ACTIVATE-to-ACTIVATE command period to different bank groups for 2KB page size	^t RRD_S (2KB)	MIN = greater of 4CK or 6ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	CK
ACTIVATE-to-ACTIVATE command period to same bank groups for 1/2KB page size	^t RRD_L (1/2KB)	MIN = greater of 4CK or 6ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	CK
ACTIVATE-to-ACTIVATE command period to same bank groups for 1KB page size	^t RRD_L (1KB)	MIN = greater of 4CK or 6ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	MIN = greater of 4CK or 5.3ns	CK
ACTIVATE-to-ACTIVATE command period to same bank groups for 2KB page size	^t RRD_L (2KB)	MIN = greater of 4CK or 7.5ns	MIN = greater of 4CK or 6.4ns	MIN = greater of 4CK or 6.4ns	MIN = greater of 4CK or 6.4ns	MIN = greater of 4CK or 6.4ns	MIN = greater of 4CK or 6.4ns	MIN = greater of 4CK or 6.4ns	MIN = greater of 4CK or 6.4ns	CK
Four ACTIVATE windows for 1/2KB page size	^t FAW (1/2KB)	MIN = greater of 16CK or 20ns	MIN = greater of 16CK or 17ns	MIN = greater of 16CK or 15ns	MIN = greater of 16CK or 13ns	MIN = greater of 16CK or 13ns	MIN = greater of 16CK or 13ns	MIN = greater of 16CK or 13ns	MIN = greater of 16CK or 13ns	ns

Memory Timing 5

- From the Command and Address Input Levels table
- From the DQ Input Receiver Specifications table
- From the Reset and Initialization description
- From the Speed Bins and Operating Conditions table
- See next slide for data sheet extracts

General I/O Memory Topology Memory Timing Board Timing Controller Diagnostics

Timing parameters as found in the data sheet of the memory device.

Parameters dependent on Speed Bin

Speed bin: -2400

tIS (base):	60	ps
tIS (base) AC level:	100	mV
tIH (base):	95	ps
tIH (base) DC level:	75	mV
tdIVW_dj:	0.1	cycles
VdiVW_total:	136	mV
tdQSQ:	66	ps
tQH:	0.38	cycles
tdQSCK:	165	ps
tdQSS:	0.27	cycles
tQSH:	0.38	cycles
tdSH:	0.18	cycles
tdSS:	0.18	cycles
tWLS:	108.0	ps
tWLH:	108.0	ps
tINIT:	500	us
tMRD:	8	cycles
tRAS:	32.0	ns
tRCD:	12.5	ns
tRP:	12.5	ns
tWR:	15.0	ns

Parameters dependent on Speed Bin, Operating Frequency, and Page Size

Update the following as you change the operating frequency, even if the device speed bin has not changed.

tRRD_S:	7	cycles
tRRD_L:	8	cycles
tFAW:	30.0	ns
tCCD_S:	4	cycles
tCCD_L:	6	cycles
tWTR_S:	3	cycles
tWTR_L:	9	cycles

Parameters dependent on Density and Temperature

Update the following as you change the physical memory device density. Incorrect values can cause data corruption.

tRFC:	160.0	ns
tREFI:	7.8	us

Memory Timing 6

Extracts from a Micron Memory DDR4 Datasheet

Table 80: Command and Address Input Levels: DDR4-1600 Through DDR4-2400

Parameter	Symbol	Min	Max	Unit	Note
AC input high voltage	$V_{IH(AQ)}$	$V_{REF} + 100$	V_{DD5}	mV	1, 2, 3
DC input high voltage	$V_{IH(DQ)}$	$V_{REF} + 75$	V_{DD}	mV	1, 2
DC input low voltage	$V_{IL(DQ)}$	V_{SS}	$V_{REF} - 75$	mV	1, 2
AC input low voltage	$V_{IL(AQ)}$	V_{SS5}	$V_{REF} - 100$	mV	1, 2, 3
Reference voltage for CMD/ADDR inputs	$V_{REFCA(DQ)}$	$0.49 \times V_{DD}$	$0.49 \times V_{DD}$	V	4

Table 82: DQ Input Receiver Specifications

Note 1 applies to the entire table

Parameter	Symbol	DDR4-1600, 1866, 2133		DDR4-2400		DDR4-2666, 3200		Unit	Notes
		Min	Max	Min	Max	Min	Max		
V_{IN} Rx mask input peak-to-peak	V_{diVW}	—	136 ¹	—	130 ¹	—	125	mV	2, 3
DQ Rx input timing window	T_{diVW}	—	0.2 ¹	—	0.2 ¹	—	0.22 ¹	UI	2, 3
DQ AC input swing peak-to-peak	$V_{IHL(AQ)}$	186	—	160	—	150	—	mV	4, 5
DQ input pulse width	T_{diPW}	0.58	—	0.58	—	0.58	—	UI	6
DQS-to-DQ Rx mask offset	1DQS2DO	-0.17	0.17	-0.17	0.17	-0.22	0.22	UI	7

Table 139: DDR4-2400 Speed Bins and Operating Conditions

DDR4-2400 Speed Bin				-083F		-083E		-083		Unit
CL-nRCD-nRP				15-15-15		16-16-16		17-17-17		
Parameter			Symbol	Min	Max	Min	Max	Min	Max	
Internal READ command to first data			¹ AA	12.5	18.00	13.32	18.00	14.16	18.00	ns
Internal READ command to first data with read DBI enabled			¹ AA_DBI	¹ AA(MIN) + 3nCK	—	¹ AA(MIN) + 3nCK	—	¹ AA(MIN) + 3nCK	—	ns
ACTIVATE to Internal READ or WRITE delay time			¹ RCD	12.5	—	13.32	—	14.16	—	ns
PRECHARGE command period			¹ RP	12.5	—	13.32	—	14.16	—	ns
ACTIVATE-to-PRECHARGE command period			¹ RAS	32	9 × ¹ REFI	32	9 × ¹ REFI	32	9 × ¹ REFI	ns
ACTIVATE-to-ACTIVATE or REFRESH command period			¹ RC	¹ RAS + ¹ RP	—	¹ RAS + ¹ RP	—	¹ RAS + ¹ RP	—	ns
READ: nonDBI	READ: DBI	WRITE	Symbol	Min	Max	Min	Max	Min	Max	Unit
CL = 9	CL = 11	CWL = 9	¹ CK	1.5	1.6	1.5	1.6	Reserved		ns
CL = 10	CL = 12	CWL = 9	¹ CK	1.5	1.6	Reserved		1.5	1.6	ns
CL = 10	CL = 12	CWL = 9, 11	¹ CK	Reserved		Reserved		Reserved		ns
CL = 11	CL = 13	CWL = 9, 11	¹ CK	Reserved		1.25	<1.5	1.25	<1.5	ns
CL = 12	CL = 14	CWL = 9, 11	¹ CK	1.25	<1.5	1.25	<1.5	1.25	<1.5	ns

Power-Up and Initialization Sequence

2. After RESET_n is de-asserted, wait for another 500µs until CKE becomes active.

Memory Timing 7

- Check tRFC is correct for the capacity of the DDR4 memory device
 - Use the tRFC1 value from the DDR4 datasheet

Refresh Timing				
REFRESH-to-ACTIVATE or REFRESH command period (all bank groups)	4Gb	tRFC1	MIN = 260	ns
		tRFC2	MIN = 160	ns
		tRFC4	MIN = 110	ns
	8Gb	tRFC1	MIN = 350	ns
		tRFC2	MIN = 260	ns
		tRFC4	MIN = 160	ns
	16Gb	tRFC1	MIN = 550	ns
		tRFC2	MIN = 405	ns
		tRFC4	MIN = 250	ns
Average periodic re-fresh interval	0°C ≤ T _C ≤ 85°C	tREFI	MIN = N/A; MAX = 7.8	μs
	85°C < T _C ≤ 95°C	tREFI	MIN = N/A; MAX = 3.9	μs

- Using the incorrect value can cause bit errors during memory accesses

Memory Timing 8

- Some timing parameters are in units of UI or UId
 - UI/UId is defined as the Unit Interval
 - Jedec specification formula : $UI = \text{minimum } [tCK(\text{avg})/2]$
 - For the DDR4 IP parameters, set $UI = tCK/2$

Table 143: Electrical Characteristics and AC Timing Parameters (Continued)

Parameter	Symbol	DDR4-1600		DDR4-1866		DDR4-2133		DDR4-2400		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
DQ Output Timing										
DQS_t, DQS_c to DQ skew, per group, per access	t ^{DQSQ}	–	0.16	–	0.16	–	0.16	–	0.17	UI _d
DQ output hold time from DQS_t, DQS_c	t ^{QH}	0.76	–	0.76	–	0.76	–	0.74	–	UI _d